

ABSTRACT

The invention relates to a method for the geometrical measurement of a material strip (2), whereby the material strip (2) defines a longitudinal direction, whereby, by means of a first measuring device with at least one radiation source (6) and with at least one detector (8), the strip thickness of the material strip (2) is determined, whereby for this purpose the radiation (10) from the radiation source (6) penetrates the material strip (2) at at least one measurement point (12) arranged in the material strip (2), and the resultant weakening of the intensity of the radiation (10) is determined by the corresponding detector (8). It is proposed that, by means of a second measuring device, the transverse contour of the material strip (2) is determined. In this situation, the measurement of the strip thickness and the transverse contour is effected at the same place on the material strip. The measured values of the thickness measurement are corrected with the measured values of the transverse contour.

The invention also relates to a device for the performance of the method.

Fig. 3 is intended for the Abstract!